

L Number	Hits	Search Text	DB	Time stamp
-	967	(BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/01 12:30
-	281	((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)) and ((ATE "automatic test equipment" tester) and (flip-flop latch selector "flip flop" flipflop "shift register"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/19 14:54
-	365	((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)).ti. ((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/19 15:05
-	300	((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)) and (buffer and control\$3 and (selector flip-flop latch selector "flip flop" flipflop "shift register"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/19 15:07
-	163	((((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)) and ((ATE "automatic test equipment" tester) and (flip-flop latch selector "flip flop" flipflop "shift register")))) and (buffer and control\$3 and (selector flip-flop latch selector "flip flop" flipflop "shift register"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/21 10:40
-	2	5235600.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/21 10:45
-	12133	(memor\$3 near test\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/29 14:18
-	12133	(memor\$3 near test\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/29 14:18
-	23	(memor\$3 near test\$3) and (BIST "self test" "built-in self-test" "in-circuit test") and ("ALPG" "programmable algorithmic pattern generator")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/29 14:28
-	28	(BIST "self test" "built-in self-test" "in-circuit test") and ("ALPG" "programmable algorithmic pattern generator")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/29 14:28
-	5	((BIST "self test" "built-in self-test" "in-circuit test") and ("ALPG" "programmable algorithmic pattern generator")) not ((memor\$3 near test\$3) and (BIST "self test" "built-in self-test" "in-circuit test") and ("ALPG" "programmable algorithmic pattern generator"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/29 14:28
-	8	(BIST BISR "built in self test" "built-in self-test" built-in-self-test) with ("programmable algorithmic pattern generator" "ALPG")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/01 12:31

-	10	(BIST BISR "built in self test" "built-in self-test" built-in-self-test) same ("programmable algorithmic pattern generator" "ALPG")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/01 12:31
-	26	(BIST BISR "built in self test" "built-in self-test" built-in-self-test) and ("programmable algorithmic pattern generator" "ALPG")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/01 13:52
-	12	(BIST BISR "built in self test" "built-in self-test" built-in-self-test) and (programmable near "pattern generator")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/01 13:53
-	12	((BIST BISR "built in self test" "built-in self-test" built-in-self-test) and (programmable near "pattern generator")) not ((BIST BISR "built in self test" "built-in self-test" built-in-self-test) and ("programmable algorithmic pattern generator" "ALPG"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/01 13:53
-	12	((BIST BISR "built in self test" "built-in self-test" built-in-self-test) and (programmable near "pattern generator")) not ((BIST BISR "built in self test" "built-in self-test" built-in-self-test) same ("programmable algorithmic pattern generator" "ALPG"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/01 13:53
-	12	((BIST BISR "built in self test" "built-in self-test" built-in-self-test) and (programmable near "pattern generator")) not ((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with ("programmable algorithmic pattern generator" "ALPG"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/01 13:53